




SETHU INSTITUTE OF TECHNOLOGY, KARIAPATTI

(An Autonomous Institution, Affiliated to Anna University, Chennai)
Pulloor, Kariapatti 626 115, Virudhunagar District, Tamil Nadu

DST-FIST SPONSORED INSTRUMENT FACILITY

SCHEME	DST- FIST <i>This facility was funded by DST through FIST programme. At present, the facility is available for internal as well as external analysis. The instruments have the following features:</i>
Instrument Name	SCANNING ELECTRON MICROSCOPE
Model & Make	GENESIS 1100
Specifications	Electron Gun: Pre-centered Tungsten Filament Magnification: x10 – x 300,000 Resolution: 3.0 nm
Photo	
Details	<i>Scanning electron microscopy (SEM) allow for targeted analysis of sample surfaces. These techniques are widely used for material surface analysis (morphology), Surface flaw/defect analysis, investigation of product failures,</i>

	<i>contaminant identification; solder joint analysis, particle size with the help of high-resolution magnifications. The Samples may be powder, thin films and Biological sample.</i>
Contact Details	Dr.S.Karthick Kumar Associate Professor Department of Physics Sethu Institute of Technology Email: karthickkumar.s@sethu.ac.in Cell: 9751285354